Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/678,061	IMAI ET AL.	
Examiner	Art Unit	
Chris C. Chu	2815	

	SEAR	CHED	
Class	Subclass	Date	Examiner
257	754 & 756	2/16/2006	C.C.
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; and IBM_TDB;	2/16/2006	C.C.